

Two-dimensional approach to fluorescence yield XANES measurement using a silicon drift detector. Erratum

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An error in the paper by Tamenori *et al.* [(2011), *J. Synchrotron Rad.* **18**, 747–752] is corrected.

In the second paragraph of §3.2 of Tamenori *et al.* (2011), we had provided incorrect fluorescence decay probability values for Mn L_{23} -shell ionization (0.0063) and O K -shell ionization (0.05). The correct fluorescence decay probability value of Mn L_{23} -shell ionization is 0.005 and that of O K -shell ionization is 0.0083 (Krause, 1979).

Consequently, we had overestimated the difference between the fluorescence decay probabilities of Mn L_{23} -shell and O K -shell ionization.

Based on the correct fluorescence decay probability values, the Mn L_{23} -shell ionization value is about 60% of the O K -shell ionization value. This ratio supports a qualitative interpretation of the dip structure that appeared in the NEXAFS spectra of a MnO crystal [Fig. 3 of Tamenori *et al.* (2011)]. Furthermore, the model proposed in the original paper was also corroborated by two-dimensional fluorescence measurement results, which have been presented in the last paragraph of §3.2. Therefore, the overall conclusions of the original paper remain unchanged.

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References

- Krause, M. O. (1979). *J. Phys. Chem. Ref. Data*, **8**, 307–327.
Tamenori, Y., Morita, M. & Nakamura, T. (2011). *J. Synchrotron Rad.* **18**, 747–752.